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# Improved Photoelectrochemical Hydrogen Gas Generation on Sb<sub>2</sub>S<sub>3</sub> Films Modified with an Earth-Abundant MoS<sub>x</sub> Co-Catalyst

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**ABSTRACT:** Antimony(III) sulfide  $(Sb_2S_3)$  has recently emerged as an outstanding potential photoelectrode due to its superlative optoelectronic properties for light-driven water splitting application. However, the occurrence of the recombination process in this material is regarded as one of the main limiting factors to date. Herein, we greatly suppressed the occurrence of recombination and improved carrier transfer via photoelectrodepositing an earth-abundant  $MoS_x$  cocatalyst over  $Sb_2S_3$  films. The  $Sb_2S_3/MoS_x$  films displayed a remarkable 2-fold increase of their photoresponse for H<sub>2</sub> generation and also resulted in shifting the onset potential approximately 100 mV to less negative values. Based on an in-depth analysis of the transients' photocurrent density, the enhanced photoresponse was assigned to a smaller probability of the electron-hole recombination process, as



noted from the substantial reduction of the accumulated negative charge density values at the surface of the  $Sb_2S_3$  films. The minimization of carriers recombination was also verified from the decrease of the charge transfer resistance values by approximately 2-fold for the  $Sb_2S_2/MoS_x$  films. Additionally,  $Sb_2S_3/MoS_x$  featured an increase of the space charge thickness, which suggests an improvement of carrier separation or a minimized recombination process due to the enlarged gradient of the (quasi-)Fermi level in the space charge region of the  $Sb_2S_3$  films.

**KEYWORDS:** antimony sulfide, molybdenum sulfide, water splitting, photoelectrochemical cells, solar energy

# INTRODUCTION

The chemist Antoine-Laurent de Lavoisier is probably one of the pioneers in studying the decomposition of water into dihydrogen (H<sub>2</sub>) and dioxygen (O<sub>2</sub>).<sup>1</sup> This initial study was particularly important at that time, as it had provided compelling evidence to rule out the phlogiston theory.<sup>2</sup> Today, the study of water splitting is highly regarded as it is considered a sustainable approach to obtain H<sub>2</sub>, which is a clean energy carrier with great potential to be one of the main sources of energy in the future. Particularly, light-driven water splitting in photoelectrochemical (PEC) cells is considered a promising approach to convert solar energy into hydrogen fuels.<sup>3</sup> In this way, a variety of semiconductor films have been assessed as photocathodes to solar-driven water splitting in an efficient and stable manner. Recently, earth-abundant and nontoxic antimony(III) sulfide (Sb<sub>2</sub>S<sub>3</sub>) film has increasingly gained considerable attention as a new alternative photocathode for H<sub>2</sub> generation in PEC cells. Such attention is due to its unique optoelectronic properties, such as its narrow indirect optical bandgap  $(E_g)$  of 1.6 eV and high absorption coefficient  $(\alpha)$  of  $10^4-10^5$  cm<sup>-1</sup> (for photons with energy greater than its Eg).<sup>4</sup> Additionally, Sb<sub>2</sub>S<sub>3</sub> has a considerable theoretical maximum photocurrent density  $(\Delta j_{ph,max})$  of ca. 24.5 mA cm<sup>-2</sup> and a substantial theoretical solar-to-hydrogen

efficiency of 28%,<sup>5</sup> which are desirable for practical application. It is also worth mentioning that  $Sb_2S_3$  is a semiconductor material having intrinsic n- or p-type conductivity, suggesting a versatile material that can be employed as a photoanode or photocathode in PEC cells, respectively.<sup>6</sup> Alongside the dual conductivity,  $Sb_2S_3$  features suitable band edge positions that straddle both water reduction and oxidation potentials for PEC H<sub>2</sub> and O<sub>2</sub> generation, respectively.<sup>5</sup>

It is fair to mention that albeit  $Sb_2S_3$  has all of these suitable properties for the light-driven hydrogen evolution reaction (HER), this material can feature a superhydrophobic surface, which is problematic to generate  $H_2$  in aqueous media.<sup>7</sup> To tackle the hydrophobicity issue, recently, we have reported a novel approach based on fast dinitrogen (N<sub>2</sub>) plasma treatment that enabled a change in the surface of the  $Sb_2S_3$ films from superhydrophobic to hydrophilic. Besides the hydrophobic issue, the occurrence of the recombination

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Deposition charge density: -500 mC cm<sup>-2</sup>.

° Bath: 2.0 mmol L<sup>-1</sup>  $(NH_4)_2$ MoS<sub>4</sub> dissolved in 0.5 mol L<sup>-1</sup> Na<sub>2</sub>SO<sub>4</sub> pH 5.

Deposition potential: -0.35 V.

process<sup>8</sup> and the possibility of Sb<sub>2</sub>S<sub>3</sub> films undergoing photocorrosion<sup>9</sup> in aqueous media are still recurring problems that need to be dealt with. In an attempt to overcome these deleterious factors, it has been demonstrated that employing a heterostructure approach, such as SnS/Sb<sub>2</sub>S<sub>3</sub> and Co<sub>3</sub>O<sub>4</sub>/Sb<sub>2</sub>S<sub>3</sub>, can potentially improve the photoelectroactivity of Sb<sub>2</sub>S<sub>3</sub> films.<sup>10,11</sup> Another promising strategy to circumvent the aforementioned problems is to deposit HER co-catalyst nanoparticles on the surface of Sb<sub>2</sub>S<sub>3</sub> films, as it can effectively minimize carrier losses by recombination that occurs under operating conditions. Employing a HER co-catalyst over a semiconductor film also allows improvement to the interfacial kinetics of carrier transfer and decrement in the overpotential of the system for the occurrence of the HER.<sup>3</sup>

Compared to the costly, and scarce, platinum (Pt), cocatalysts based on molybdenum disulfide (MoS<sub>2</sub>) and amorphous molybdenum sulfide (MoS<sub>x</sub>, x = 2 or 3) have gained considerable attention in the last decades for being less costly, earth-abundant, and having an outstanding catalytic activity to drive the HER.<sup>12,13</sup> Additionally, MoS<sub>x</sub> particularly also proves to be advantageous in terms of economical synthesis as it does not require annealing, which is usually necessary to obtain crystalline MoS<sub>2</sub>.<sup>14</sup> MoS<sub>x</sub> can be prepared over a semiconductor material by photoelectrodeposition, and that can be carried out potentiostatically<sup>15</sup> or galvanostatically.<sup>16</sup> The photoelectrodeposition stands advantageously as it allows selectively depositing the co-catalyst at locations where photogenerated electrons are readily available on the semiconductor surface. This ensures greater efficiency in the use of the co-catalyst since it will be placed at locations where the PEC HER most likely takes place.<sup>17</sup> The  $MoS_x$  photoelectrodeposition procedure on a p-type semiconductor film (photocathode) consists of initially placing the film in a solution containing the tetrathiomolybdate ion  $([MoS_4]^{2-})$ precursor. Once this system is under illumination and polarization, the following events occur: (i) absorption of light by the photocathode followed by the generation of an electron in the conduction band  $(e_{CB}^{-})$  and holes in the valence

band  $(h_{VB}^+)$ ; (ii) migration of the  $e_{CB}^-$  to the photocathodel electrolyte interface; and (iii) transfer of the  $e_{CB}^-$  to reduce  $[MoS_4]^{2-}$  ions to  $MoS_2$  (cf. eq 1), which is subsequently assembled, preferably, at the active sites of the photocathode surface.<sup>3,15</sup>

$$[MoS_4]_{(aq)}^{2^-} + 2H_2O_{(1)} + 2e_{CB}^-$$
  

$$\rightarrow MoS_{2(s)} + 2HS_{(aq)}^- + 2OH_{(aq)}^-$$
(1)

Regarding the photoelectrodeposition of  $MoS_x$  nanoparticles over  $Sb_2S_3$  films for PEC H<sub>2</sub> generation, to the best of our knowledge, no such study has been reported yet. The studies in the literature about the  $Sb_2S_3/MoS_x$  films assess this system as an anode for the application of sodium-ion batteries.<sup>18,19</sup> Only recently, efforts have been made on improving the photocurrent density ( $\Delta j_{ph}$ ) response for the HER on  $Sb_2S_3$ film via deposition of Pt nanoparticles over  $Sb_2S_3$ -based heterostructures, namely, CuInS<sub>2</sub>/Sb<sub>2</sub>S<sub>3</sub>/Pt<sup>20</sup> and Sb<sub>2</sub>S<sub>3</sub>/CdS/ TiO<sub>2</sub>/Pt.<sup>5</sup>

On the strength of what has been said and aiming to improve the photoelectroactivity of Sb<sub>2</sub>S<sub>3</sub> films for H<sub>2</sub> generation, we herein propose the novel system based on plasma-treated  $Sb_2S_3$  (PT- $Sb_2S_3$ ) films superficially modified with nanoparticles of  $MoS_x$ . Both  $Sb_2S_3$  and  $MoS_x$  were obtained by electrodeposition, which is well known for being economical, simple (not requiring sophisticated systems/ equipment), and easily scalable. Particularly, we investigated in this work the effect of MoS<sub>x</sub> photoelectrodeposition time on the photoelectroresponse of the  $PT-Sb_2S_3/MoS_x$  system for the HER. We demonstrated that the  $MoS_x$  photoelectrodeposition time did not significantly influence the photoelectroresponse of  $PT-Sb_2S_3/MoS_r$ . Nevertheless, the presence of  $MoS_r$ revealed substantial improvement of the photoelectrocatalytic properties of PT-Sb<sub>2</sub>S<sub>3</sub> films for the HER, as observed by the improvement of  $\Delta j_{ph}$  response and shifting of the onset potential  $(E_{on})$  toward less negative values. Furthermore, we demonstrated that the presence of  $MoS_x$  nanoparticles enabled a decrease of carrier recombination on the surface of  $PT-Sb_2S_3$ 

films as well as a noticeable reduction in charge transfer resistance  $(R_{rf})$  at the semiconductorlelectrolyte interface.

## EXPERIMENTAL SECTION

Synthesis and Surface Modifications of the Sb<sub>2</sub>S<sub>3</sub> Films. The synthesis of the Sb<sub>2</sub>S<sub>3</sub> films over glass-coated fluorine-doped tin oxide (FTO) substrate can be found in our previous work.<sup>7</sup> Briefly, the synthesis of the Sb<sub>2</sub>S<sub>3</sub> films consisted of initially electrodepositing Sb films potentiostatically at -1.14 V vs Ag/AgCl/Cl<sub>(sat.KCl)</sub><sup>-</sup> with a deposition charge density of -500 mC cm<sup>-2</sup>. The electrodeposition bath was a freshly made solution of 6 mmol L<sup>-1</sup> K<sub>2</sub>Sb<sub>2</sub>(C<sub>4</sub>H<sub>2</sub>O<sub>6</sub>)<sub>2</sub> dissolved in 0.1 mol L<sup>-1</sup> KNa(C<sub>4</sub>H<sub>4</sub>O<sub>6</sub>) at pH 6 (pH adjusted with diluted H<sub>2</sub>SO<sub>4</sub>), which was the supporting electrolyte and complexing agent. The as-electrodeposited Sb films were subjected to a sulfurization treatment at 300 °C for 3 h under a sublimated S atmosphere to obtain the Sb<sub>2</sub>S<sub>3</sub> phase. As depicted in our latest work,<sup>10</sup> the employed sulfurization system consisted of a partially closed cylindrical glass, which contained the samples and 0.1 g of elemental S powder as the sulfide source. This closed cylindrical glass was placed in a tubular furnace (EDGCON SP) with a flux of Ar gas.

Then, the  $Sb_2S_3$  films were treated under  $N_2$  plasma for 10 s in a plasma cleaner equipment (Zhengzhou CY-P2L-B). As reported in our latest work, the purpose of the plasma treatment was to turn the superhydrophobic surface of the  $Sb_2S_3$  films into hydrophilic, which is an essential condition for efficient  $H_2$  production via water splitting.<sup>7</sup>

Sequentially, the surface of the PT-Sb<sub>2</sub>S<sub>3</sub> films was modified with nanoparticles of  $MoS_x$  co-catalyst via the photoelectrodeposition method. This experiment consisted of front-illuminating the PT-Sb<sub>2</sub>S<sub>3</sub> films and concomitantly applying -0.35 V vs Ag/AgCl/Cl<sub>(sat. KCl)</sub><sup>-</sup> (the deposition potential was determined from cyclic voltanmetry analyses as shown in Figure S1) during different deposition times, i.e., 1, 10, and 20 min, and the samples were labeled as PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub>.

The PEC system setup was composed of a solar simulator (Oriel LCS-100 with a 100 W Xe lamp coupled to an AM1.5G filter) with an irradiance of 100 mW cm<sup>-2</sup>, and a three-electrode cell having a quartz window. The working electrode (WE) was the PT-Sb<sub>2</sub>S<sub>3</sub> films, while the reference (RE) and counter electrodes were an Ag/AgCl/ Cl<sub>(sat. KCl)</sub><sup>-</sup> and Pt plate, respectively. All potential values are quoted with respect to this RE (197 mV vs reversible hydrogen electrode (RHE) at 25 °C) whose potential was constantly checked before and after each measurement, and its value did not show any significant variation. The employed deposition bath was a freshly prepared solution of 2.0 mmol  $L^{-1}$  (NH<sub>4</sub>)<sub>2</sub>MoS<sub>4</sub>, as Mo and S precursors, dissolved in 0.5 mol  $L^{-1}$  Na<sub>2</sub>SO<sub>4</sub> at pH 5 (pH adjusted with diluted H<sub>2</sub>SO<sub>4</sub>), which was the supporting electrolyte. Prior to every experiment, this solution was saturated with N<sub>2</sub>. The MoS<sub>\*</sub> deposition bath was adapted from the methodology reported by Tran et al.<sup>15</sup> A summary of all of the steps involved in the preparation of the films is depicted in Scheme 1.

Physical and Chemical Characterization of the Films. The crystalline structure of the films was analyzed using an X-ray diffractometer (Shimadzu XRD-6000) with Cu K-L<sub>3</sub> (K $\alpha_1$ ) radiation (1.54 Å). The diffractograms were recorded at a scan speed of  $0.20^{\circ}$ min<sup>-1</sup> and a sampling pitch of 0.02°. The diffraction peaks indexations were handled with the Crystallographica Search-Match (version 2, 1, 1, 1) software.<sup>21</sup> The films' morphological investigation was carried out on a high-resolution field emission scanning electron microscope (FE-SEM, ZeissSupra 35). The chemical analysis of the films was performed employing an energy-dispersive X-ray spectrometer (Bruker XFlash 6l60 detector) coupled with the FE-SEM (Philips XL-30). For a further chemical understanding of the films, an X-ray photoelectron spectrophotometer (Scienta Omicron) with a monochromatic Al K-L<sub>3</sub> (K $\alpha_1$ ) radiation (1486.7 eV) was employed. The high-resolution spectra of the C 1s, N 1s, S 2p, Mo 3d, and Sb 3d core levels were recorded with an energy step of 0.05 eV at a pass energy of 50 eV. For the data processing, all of the spectra were calibrated with the C 1s peak at 284.8 eV. The spectra background was fitted using a U3 Tougaard function, and the peaks were fitted with a GaussianLorentzian lineshape, namely, LA ( $1 \le a \le 10, 0 \le b \le 15, 80 \le m \le 500$ ), where *a* and *b* are the Lorentzian contribution terms and *m* is the width of the Gaussian. All of the spectra analyses were handled with the CasaXPS (version 2.3.19PR1.0) software.<sup>22</sup> The estimation of the optical  $E_g$  was achieved utilizing an ultraviolet–visible–near-infrared (UV–vis–NIR) spectrophotometer (Varian Cary 5) at diffuse reflectance mode.

**Photoelectrochemical Assessment of the Films.** The PEC assessment study aimed to evaluate the photoelectroactivity of the synthesized films for H<sub>2</sub> generation via light-driven water splitting. For this study, the main parameter used to assess the films' photoelectroactivity for the HER was the generated cathodic  $\Delta j_{\rm ph}$  signal, which is directly proportional to the amount of H<sub>2</sub> generated. This parameter was obtained from the linear sweep voltammetry curves both in the dark and under illumination, which was scanned from the open-circuit potential ( $E_{\rm oc}$ ) to -0.40 V at a scan rate of 50 mV s<sup>-1</sup>. Additional experiments based on chronoamperometry measurements at -0.2 V (potential for the HER at pH 0.6) and under chopped light were carried out to analyze the dynamics of the photogenerated carriers.

For a further understanding of the films' photoelectroactivity, electrochemical impedance spectroscopy (EIS) experiments were conducted. These experiments were performed under constant illumination, and the films were polarized at -0.2 V, which is the potential for the HER at pH 0.6. The impedance spectra were obtained in a frequency range of 100 kHz to 0.1 Hz and a root mean square (rms) amplitude of 10 mV. The spectra were modeled to an equivalent electric circuit using the ZView (version 3.1c) software. As an additional characterization of the films, the Mott–Schottky plots were obtained to determine the flatband potential ( $E_{\rm fb}$ ) and semiconductor conductivity type (n- or p-type). The experiments were conducted applying a sinusoidal excitation signal of 10 mV<sub>rms</sub> and a frequency of 1.0 kHz, which is the most used in the literature for the Sb<sub>2</sub>S<sub>3</sub>.<sup>5,23</sup> The applied potential range was from the  $E_{\rm oc}$  to -0.20 V (divided into 15 points) with an equilibrium time of 1 min prior to every applied potential.

All of these experiments were performed employing the PEC system setup described at the beginning of this experimental section and using a N<sub>2</sub>-saturated solution of 1.0 mol  $L^{-1}$  H<sub>2</sub>SO<sub>4</sub> at its natural pH of 0.6. We have chosen this electrolyte because MoS<sub>x</sub> is more effective to electrocatalyze the HER in strong acid media (pH 0 or 1).<sup>16</sup> The WE, namely, the Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films, was front-illuminated.

## RESULTS AND DISCUSSION

Prior to the investigation of the  $Sb_2S_3/MoS_x$  films for PEC H<sub>2</sub> generation, initially, we assessed whether to photoelectrodeposit  $MoS_x$  over the untreated or plasma-treated  $Sb_2S_3$  film. In this way,  $MoS_x$  was then deposited onto untreated  $Sb_2S_3$ (labeled as UT-Sb<sub>2</sub>S<sub>3</sub>) and PT-Sb<sub>2</sub>S<sub>3</sub> films polarized at -0.35V and under illumination for 10 min. The photoelectroactivity of UT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films for H<sub>2</sub> generation was assessed by linear sweep voltammetry both in the dark and under illumination (see Figure S2). Compared with the UT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> film, the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> film displayed an overwhelmingly higher cathodic  $\Delta j_{\rm ph}$  response over the entire range of potential values. Taking the cathodic  $\Delta j_{\rm ph}$  value at -0.2 V, which is the potential for the HER at pH 0.6, the UT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films presented values of -0.02 and -1.00 mA cm<sup>-2</sup>, respectively. The diminished photoresponse for  $UT-Sb_2S_3/MoS_x$  film is due to the superhydrophobic nature of the UT-Sb<sub>2</sub>S<sub>3</sub> film, as previously reported in our latest work.<sup>7</sup> This superhydrophobic behavior for UT-Sb<sub>2</sub>S<sub>3</sub> film also resulted in impeding the deposition of  $MoS_x$ . This was verified by the absence of the characteristic peaks of MoS<sub>2</sub> in the Mo 3d spectrum (see Figure S3), which only displayed peaks corresponding to S  $2s^{24}$ 

assigned to probably Sb<sub>2</sub>S<sub>3</sub>. The superhydrophobicity of the UT-Sb<sub>2</sub>S<sub>3</sub> film compromised the deposition of  $MoS_x$  as it prevented  $[MoS_4]^{2-}$  species from reaching the UT-Sb<sub>2</sub>S<sub>3</sub> surface. Based on the general electrodeposition steps,<sup>25</sup> the attraction of  $[MoS_4]^{2-}$  ions onto the film's surface is critically important for the subsequent deposition steps, namely, adsorption of  $[MoS_4]^{2-}$  species followed by their discharge. Since the surface of the UT-Sb<sub>2</sub>S<sub>3</sub> film is highly hydrophobic, none of these aforementioned deposition steps took place due to the poor affinity of  $[MoS_4]^{2-}$  ions to be drawn to the surface of the UT-Sb<sub>2</sub>S<sub>3</sub> film.

In light of the impossibility to deposit  $MoS_x$  on  $UT-Sb_2S_3$ films, we decided to perform the deposition of this compound over the PT-Sb<sub>2</sub>S<sub>3</sub> films, and for this study, the deposition time was systematically investigated. The PT-Sb<sub>3</sub>S<sub>3</sub> and PT-Sb<sub>3</sub>S<sub>3</sub>/ (1, 10, or 20 min)-MoS<sub>x</sub> films initially were characterized in terms of their physical, chemical, and optical properties, as presented hereinafter.

Physical, Chemical, and Optical Characterization of the Films. The microstructural nature for bare  $PT-Sb_2S_3$  and  $PT-Sb_2S_3/(20 \text{ min})-MoS_x$  films were assessed employing X-ray diffraction (XRD) patterns, and the results are displayed in Figure 1. For this analysis, we only employed the longest  $MoS_x$ 



**Figure 1.** XRD patterns for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(20 min)-MoS<sub>x</sub> films. Reference patterns for Sb<sub>2</sub>S<sub>3</sub> (Powder Diffraction File (PDF) no. 42-1393),<sup>26</sup> 2H-MoS<sub>2</sub> (PDF no. 37-1492),<sup>27</sup> and 3R-MoS<sub>2</sub> (PDF no. 89-3040)<sup>28</sup> are also shown. The diffraction peaks labeled with hashes (#) are assigned to the SnO<sub>2</sub> (PDF no. 41-1445)<sup>29</sup> from the FTO coating on a glass substrate.

photoelectrodeposition time (20 min) as it could provide facilitation in the detection of the  $MoS_x$  due to the greater amount of the deposited  $MoS_x$ .

According to Figure 1, all of the diffraction peaks labeled with asterisks (\*) were indexed to crystalline orthorhombic  $Sb_2S_3$  phase with a *Pbnm* space group for both samples. For the superficially modified film, we expected to photoelectrodeposit the  $MoS_2$  compound; however, we have not observed any additional diffraction peaks referring to any of the main  $MoS_2$  phases, namely, 2H and 3R phases.<sup>30</sup> This result means that the photoelectrodeposition of  $MoS_2$  under these conditions

may have led to an amorphous or nanocrystalline material formation (referred to as  $MoS_x$ ), which is consistent with studies in the literature that (photo)electrodeposited  $MoS_x$  is usually amorphous.<sup>31,32</sup>

The PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films were also characterized in terms of their morphology by scanning electrons microscopy (SEM) micrographs as shown in Figure 2. The morphology of the PT-Sb<sub>2</sub>S<sub>3</sub> film seems to feature round-shaped agglomerations having particle lengths of approximately 325 nm, as shown in the particle size distribution histograms of Figure S4. For the  $Sb_2S_3/(1 \text{ min})$ - $MoS_x$  film, despite not observing any obvious modifications, we believe that very small clusters/particles of  $MoS_r$  were deposited all over the film as there was a significant improvement of the film's photoelectrocatalytic properties (further presented below). Increasing the  $MoS_x$  photoelectrodeposition time for 10 and 20 min resulted in substantial superficial modification of the films compared to the bare one, which suggests that the  $MoS_x$  may have been deposited in a greater amount on the PT-Sb<sub>2</sub>S<sub>3</sub> films. As also indicated in the inset of Figure 2, it is noted that the roundshaped agglomerations of the PT-Sb<sub>2</sub>S<sub>3</sub> films seem to have a rougher surface once modified with the MoS<sub>r</sub> photoelectrodeposited for 10 and 20 min. Based on these results, it is evident that increasing the  $MoS_x$  photoelectrodeposition time significantly changes the films' surface, as well as leading to thorough coverage of the PT-Sb<sub>2</sub>S<sub>3</sub> films.

Aiming to chemically characterize the PT-Sb<sub>2</sub>S<sub>3</sub> and PT- $Sb_2S_3/(1, 10, or 20 min)$ -MoS<sub>r</sub> films, energy-dispersive X-ray spectra (EDS) were recorded for those films and are depicted in Figure S5. As noted, the EDS spectrum for the PT-Sb<sub>2</sub>S<sub>3</sub> film displayed the Sb and S characteristic peaks, which provided an S/Sb atomic ratio of 1.6, as listed in Table S1 and Figure S6. Albeit EDS is a semiquantitative technique, the obtained S/Sb atomic ratio is very close to the expected stoichiometric composition, i.e., S/Sb = 1.5. Regarding the PT- $Sb_2S_3/MoS_x$  films, the Mo K-L<sub>3</sub> (K $\alpha_1$ ) peak at 17.5 keV<sup>33</sup> (signaled by a red vertical line in the inset of Figure S5) was not observed. Such a result suggests that even though the films were superficially modified, as seen from SEM images in Figure 2, the deposited amount of  $MoS_x$  is very low. Moreover, as shown in Table S1 and Figure S6, the atomic percentage of Sb and S continuously decreases over the MoS<sub>x</sub> photoelectrodeposition time, implying that the detection of such elements is hindered due to the deposited overlayer. To verify the presence and homogeneity distribution of the photoelectrodeposited MoS<sub>x</sub> over the film's surface, EDS elemental mapping images were obtained and are shown in Figure 3. For the superficially modified films, we were able to confirm the presence of the  $MoS_r$  for all of the photoelectrodeposition times and that this compound was evenly distributed over the PT-Sb<sub>2</sub>S<sub>3</sub> films. Additionally, for the bare PT-Sb<sub>2</sub>S<sub>3</sub> film, the Sb and S elements are homogeneously distributed throughout the film.

Further chemical analyses of the films were performed by Xray photoelectron spectroscopy (XPS) to confirm the presence of Sb, Mo, and S elements as well as their oxidation states and chemical bonding. For this study, the XPS spectra (see Figure 4) of the bare PT-Sb<sub>2</sub>S<sub>3</sub> film was obtained including the ones having  $MoS_x$  photoelectrodeposited for 1 and 10 min as these deposition times provided the highest mean photoresponses (shown in Figure 6b). According to Figure 4a, the Sb 3d spectrum for the bare PT-Sb<sub>2</sub>S<sub>3</sub> film displayed photoemission



Figure 2. SEM micrographs with a magnification of  $150k\times$  for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films.



Figure 3. EDS elemental mapping images of Sb, S, and Mo with a magnification of  $10k \times$  for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films.

peaks for Sb  $3d_{5/2}$  and  $3d_{3/2}$  doublets at 531.0 and 540.4 eV, respectively, which were assigned to Sb<sup>3+</sup> in Sb<sub>2</sub>S<sub>3</sub>.<sup>34,35</sup> The additional peak at 532.1 eV (O 1s) is probably attributed to adsorbed atmospheric oxygen (O<sub>2</sub>, water vapor, etc.) in the S vacancies that can be generated by the ejection of S atoms during the N<sub>2</sub> plasma treatment.<sup>36</sup> For the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films, the Sb 3d spectra did not show the appearance of new photoemission peaks. Additionally, the Sb  $3d_{5/2}$  and  $3d_{3/2}$  peaks were not significantly shifted compared to the unmodified film, meaning that the chemical environment of Sb<sup>3+</sup> species was not modified. Concerning the Mo 3d spectra (cf. Figure 4b), the PT-Sb<sub>2</sub>S<sub>3</sub> film presented a photoemission peak at 232.8 eV for the S 2s, which overlaps with the Mo 3d region, and this peak might be associated with the occurrence of nitrogen bonded to sulfur (S–N).<sup>37–39</sup> This result confirms

once again what was reported in our previous study that the nitrogen ions from the plasma treatment are very likely to be bonded to sulfur atoms of the  $Sb_2S_3$  film surface.<sup>7</sup> It is worth mentioning that the presence of the superficial S–N group is particularly significant as it is responsible for the hydrophilic behavior of the  $Sb_2S_3$  films once treated under N<sub>2</sub> plasma.<sup>7</sup>

Still, in Figure 4b, the profile of the Mo 3d spectra changed dramatically for the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films. For both MoS<sub>x</sub> photoelectrodeposition times, the spectra showed photoemission peaks of Mo  $3d_{5/2}$  at ca. 230.0 eV and Mo  $3d_{3/2}$  at ca. 233.2 eV, in which Mo<sup>4+</sup> species are represented in MoS<sub>2</sub>.<sup>40-42</sup> Low-intensity peaks were also noted at approximately 233.0 eV (Mo  $3d_{5/2}$ ) and 236.2 eV (Mo  $3d_{3/2}$ ) assigned to Mo<sup>6+</sup> present as molybdenum(VI) oxide (MoO<sub>3</sub>)<sup>41,43</sup> and/or as molybdenum oxysulfide (MoO<sub>x</sub>S<sub>y</sub>).<sup>44,45</sup>



Figure 4. High-resolution XPS spectra of (a) Sb 3d, (b) Mo 3d, (c) S 2p, (d) N 1s core levels for  $PT-Sb_2S_3$  and  $PT-Sb_2S_3/(1 \text{ or } 10 \text{ min})-MoS_x$  films.

This  $MoO_3$  or  $MoO_xS_y$  may have arisen from the air exposure oxidation process or during the deposition process as the produced OH<sup>-</sup> ions (see eq 1) might have facilitated the formation of the MoO<sub>3</sub> or MoO<sub>x</sub>S<sub>y</sub> compound.<sup>46</sup> The Mo 3d spectra for the films modified with MoS, also displayed the S 2s peak at ca. 226 eV assigned to MoS<sub>2</sub>.<sup>41</sup> Regarding the S 2p spectra (see Figure 4c), the photoemission peaks at 169.5 and 168.5 eV for the PT-Sb<sub>2</sub>S<sub>3</sub> film were attributed to the occurrence of the S–N bond.<sup>37,38,47</sup> Such a result backs up what has already been discussed in Figure 4b for the PT-Sb<sub>2</sub>S<sub>3</sub> film that the  $N_2$  plasma treatment leads to the formation of the S-N bond on the surface of Sb<sub>2</sub>S<sub>3</sub> film. For the PT-Sb<sub>2</sub>S<sub>3</sub> films modified with  $MoS_{xy}$  the S 2p spectra did not display the photoemission peaks assigned to the S-N bond. We believe this may be due to the presence of  $MoS_r$  over the PT-Sb<sub>2</sub>S<sub>3</sub> films that hinders the detection of the S-N bond signal. It was also noted that the S 2p spectra for the PT-Sb<sub>2</sub>S<sub>3</sub> films modified with  $MoS_x$  presented photoemission peaks at approximately 161.5 eV (S  $2p_{3/2}$ ) and 162.5 eV (S  $2p_{1/2}$ ), which correspond to S<sup>2-</sup> specie in MoS<sub>x</sub>.<sup>46,48</sup> The additional peaks at 162.6 eV (S  $2p_{3/2}$ ) and 163.6 eV (S  $2p_{1/2}$ ) are associated with  $S_2^{2^-}$  ion in  $MoS_x^{-46,48}$  According to Ting et al.,<sup>14</sup> the peaks having the lowest binding energies correspond to unsaturated  $S^{2-}$  and terminal  $S_2^{2-}$ , while the ones with the highest binding energy correspond to the bridging  $S_2^{2-}$  and

apical S<sup>2-</sup>. It is worth mentioning that a finer assignment of these different sulfide species at a particular binding energy value is quite difficult to be carried.<sup>14</sup> Nevertheless, among these sulfide species, Ting et al.<sup>14</sup> reported that the bridging  $S_2^{2^-}$  is the one that provides the most active site in the MoS<sub>x</sub> for the occurrence of the HER. Finally, for the N 1s spectra (vide Figure 4d), the photoemission peak at 401.7 eV for the PT-Sb<sub>2</sub>S<sub>3</sub> film is assigned quite possibly to the S-N bond.<sup>38,39,49</sup> This serves as additional evidence of what was discussed previously about the formation of the S-N bond during the N<sub>2</sub> plasma treatment. Additionally, the occurrence of the S-N bond was not observed for the untreated film as no signal was displayed in the N 1s spectrum for  $UT-Sb_2S_3/MoS_x$ film (cf. Figure S3d). Such a result further verifies that the formation of the S-N group on the Sb<sub>2</sub>S<sub>3</sub> films' surface only occurs if the Sb<sub>2</sub>S<sub>3</sub> films are treated under N<sub>2</sub> plasma. Still regarding Figure 4d, compared to the bare PT-Sb<sub>2</sub>S<sub>3</sub> film, the peak of the S-N bond shifted 2.2 and 2.8 eV toward lower binding energy values for the films having MoS<sub>x</sub> photoelectrodeposited for 1 and 10 min, respectively. Such shifting may be an indication that the chemical surroundings of the N atoms were modified by the deposited MoS<sub>x</sub>. The N 1s spectra for PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films featured an additional peak at ca. 396 eV, which arises from the Mo  $3p_{3/2}$  of the MoS<sub>2</sub> that is

overlapped in the N 1s region.<sup>41</sup> The assignment of all photoemission peaks is summarized in Table S2.

Regarding the optical characterization of the films, Tauc plots (cf. Figure 5) were obtained to estimate the optical  $E_{g}$ 



**Figure 5.** Tauc plots and reflectance spectra (inset) of  $PT-Sb_2S_3$  and  $PT-Sb_2S_3/(1, 10, \text{ or } 20 \text{ min})-MoS_x$  films.

value for an indirect (allowed) electronic transition. The PT-Sb<sub>2</sub>S<sub>3</sub> film presented an estimated optical  $E_g$  value of 1.66  $\pm$  0.01 eV, which is in agreement with the one reported in the literature.<sup>4</sup> Estimated optical  $E_g$  values of 1.66  $\pm$  0.01, 1.65  $\pm$  0.01, and 1.66  $\pm$  0.01 eV were obtained for the PT-Sb<sub>2</sub>S<sub>3</sub> films superficially modified with MoS<sub>x</sub> photoelectrodeposited for 1, 10, and 20 min, respectively. As noted, the  $E_g$  value for the PT-Sb<sub>2</sub>S<sub>3</sub> films was not altered once superficially modified with the MoS<sub>x</sub>, meaning that no doping effect occurred in the Sb<sub>2</sub>S<sub>3</sub> films during the photoelectrodeposition of the MoS<sub>x</sub>. Interestingly, it is reported that MoS<sub>2</sub> has a layer-dependent optical  $E_g$  value, that is, bulk MoS<sub>2</sub> features an indirect (allowed) optical  $E_g$  of 1.3 eV and a direct (allowed) optical  $E_g$  of 1.9 eV once thinned down to a monolayer.<sup>30,50</sup> Nevertheless, in this work, we have not observed the  $E_g$  value for the bulk MoS<sub>2</sub> from the Tauc plots in Figure 5. The reason why

the  $E_{\rm g}$  of this material was not observed may be related to the existence of amorphous MoS<sub>2</sub>.

It is worth pointing out that the superficial modification of a semiconductor film may result in optical losses, such as reflection, which is deleterious for solar harvesting applications. In this way, we recorded the reflectance spectra of the PT-Sb<sub>2</sub>S<sub>3</sub> and the PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films, and the results are presented as an inset figure in Figure 5. Compared to the bare PT-Sb<sub>2</sub>S<sub>3</sub> film, the spectra did not display significant variation of the reflectance values in the visible range (ca. 590–750 nm). There was only an increase of the reflectance values (up to 36%) for the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films in the near-infrared range (ca. 780–1033 nm) of the spectra. Based on these results, the deposition of MoS<sub>x</sub> particles over the PT-Sb<sub>2</sub>S<sub>3</sub> films did not result in significant optical losses due to reflection in the absorption range, i.e., visible range, of the semiconductor.

In addition to the physical, chemical, and optical characterization, the  $PT-Sb_2S_3$  films before and after superficially modified with  $MoS_x$  were assessed for PEC H<sub>2</sub> generation, as presented hereinafter.

**Photoelectrochemical Assessment of the Films.** The PEC assessment of the films consisted of initially recording linear sweep voltammograms in the dark and under the solar simulator, which is depicted in Figure 6a.

As seen in Figure 6a, all of the films presented p-type conductivity behavior as a cathodic  $\Delta j_{\rm ph}$  signal was generated. Considering the employed electrolyte, namely, N<sub>2</sub>-saturated 1.0 mol L<sup>-1</sup> H<sub>2</sub>SO<sub>4</sub> at its natural pH of 0.6, such cathodic  $\Delta j_{\rm ph}$  response is attributed to the light-driven HER (eqs 2 and 3)<sup>51</sup> on the films.

$$2h\nu \to 2h_{VB}^+ + 2e_{CB}^- \tag{2}$$

$$2H_3O_{(aq)}^+ + 2e_{CB}^- \rightarrow H_{2(g)} + 2H_2O_{(l)}$$
 (3)

in which  $h\nu$  is the photon energy to generate  $e_{CB}^{-}$  and  $h_{VB}^{+}$  in the semiconductor.

It was also noted that there was an improvement in PEC H<sub>2</sub> generation as the cathodic  $\Delta j_{ph}$  responses were higher in the entire range of potentials for the PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films in comparison to the bare PT-Sb<sub>2</sub>S<sub>3</sub> film. In terms



**Figure 6.** (a) Linear sweep voltammograms at a scan rate of 50 mV s<sup>-1</sup> in the dark and under solar light simulator (AM1.5G and 100 mW cm<sup>-2</sup>) and (b) mean  $\Delta j_{ph}$  values at -0.2 V vs Ag/AgCl/Cl<sub>(sat. KCl)</sub><sup>-</sup> for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films. The electrolyte was a N<sub>2</sub>-saturated solution of 1.0 mol L<sup>-1</sup> H<sub>2</sub>SO<sub>4</sub> at pH 0.6.



Figure 7. (a) Transient  $\Delta j_{ph}$  responses at -0.2 V vs Ag/AgCl/Cl<sub>(sat. KCl)</sub><sup>-</sup> and under a chopped solar light simulator (AM1.5G and 100 mW cm<sup>-2</sup>) and (b)  $\sigma_{acc}$  values at -0.2 V vs Ag/AgCl/Cl<sub>(sat. KCl)</sub><sup>-</sup> for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films. The electrolyte was a N<sub>2</sub>-saturated solution of 1.0 mol L<sup>-1</sup> H<sub>2</sub>SO<sub>4</sub> at pH 0.6.

of  $\Delta j_{\rm ph}$  values at -0.2 V (corresponds to 0 V vs RHE), as summarized in Figure 6b, the  $PT-Sb_2S_3$  films having  $MoS_x$ photoelectrodeposited for 1, 10, and 20 min presented values of  $-0.86 \pm 0.12$ ,  $-0.89 \pm 0.16$ , and  $-0.72 \pm 0.02$  mA cm<sup>-2</sup>, respectively. These values indicated that there was not a dependency of the  $MoS_x$  photoelectrodeposition time with the photoelectroactivity of the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films. However, the presence of the  $MoS_x$  over the  $PT-Sb_2S_3$  films provided an approximately 2-fold increase in the cathode  $\Delta j_{ph}$  response compared to the bare PT-Sb<sub>2</sub>S<sub>3</sub> film ( $-0.40 \pm 0.05$  mA cm<sup>-2</sup>). It was also noticed from Figure 6a that modifying the PT-Sb<sub>2</sub>S<sub>3</sub> film surface with  $MoS_x$  resulted in shifting the  $E_{on}$  in ca. 100 mV toward less negative values, which is due to the catalytic activity of MoS<sub>x</sub> for the HER.<sup>52</sup> This catalytic behavior is probably associated with the presence of  $S_2^{2-}$  species<sup>14</sup> in  $MoS_{xy}$  as observed in the S 2p XPS spectra (see Figure 4c). Additionally, the  $E_{on}$  shift toward less negative values stands advantageously as it facilitates the occurrence of the HER by diminishing the energy input or the overpotential of the system  $(PT-Sb_2S_3/MoS_x \text{ films}).$ 

Further PEC analysis of the bare PT-Sb<sub>2</sub>S<sub>3</sub> and the PT- $Sb_2S_3/(1, 10, or 20 min)$ -MoS<sub>x</sub> films were performed by means of the transients'  $\Delta j_{\rm ph}$  measurements at -0.2 V and under chopped illumination. As can be noted in Figure 7a, under illumination, the transients'  $\Delta j_{\rm ph}$  profile for all of the films featured a sharp cathodic  $\Delta j_{ph}$  rise followed by an exponential decay, known as a spike. The existence of spikes is associated with the occurrence of the electron-hole recombination process at the semiconductor surface,<sup>53</sup> as observed for a variety of semiconductor materials.<sup>53–56</sup> Once the illumination was interrupted, an anodic current density overshoot was observed, which is attributed to the recombination of holes with electrons accumulated or trapped on surface states.<sup>57</sup> Such a phenomenon is known as back-electron-hole recombination because there is a backflow of holes from the semiconductor's bulk toward its surface to recombine with the accumulated electrons.5

Aiming at a quantitative analysis of the transients, the spike curves in Figure 7a were integrated as it provides the accumulated charge density ( $\sigma_{acc}$ ), which is proportional to the number of negative charges (electrons) accumulated at the surface.<sup>54</sup> It is interesting to point out that the calculated  $\sigma_{acc}$  values can also be represented by the area of the spike (cf. the

inset of Figure 7b). For this study, the  $\sigma_{\rm acc}$  value of the last  $\Delta j_{\rm ph}$ transient for bare PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)- $MoS_x$  films was calculated, and the results are exhibited in Figure 7b. The  $\sigma_{\rm acc}$  value slightly changed over the photoelectrodeposition time of  $MoS_x$  on PT-Sb<sub>2</sub>S<sub>3</sub>, and similar trending was observed for the  $\Delta j_{ph}$  response (see Figure 6b). Additionally, the  $\sigma_{acc}$  value dramatically diminished by a factor of 8.4 for  $PT-Sb_2S_3/MoS_x$  films in comparison with bare PT- $Sb_2S_3$  film (from -86.3 to -10.3  $\mu$ C cm<sup>-2</sup>). This result indicates that a certain amount of photogenerated electrons may have been accumulated on the surface of the  $PT-Sb_2S_3$ films as the reduced  $\sigma_{\rm acc}$  values only occurred for PT-Sb<sub>2</sub>S<sub>3</sub> films superficially modified with MoS<sub>x</sub>. No doping occurred during the superficial modification of PT-Sb<sub>2</sub>S<sub>3</sub> films with  $MoS_x$  as there was neither variation of the  $E_g$  values (vide Figure 5) or shifting of the diffraction peaks (see Figure 1), and this comes as additional evidence that the photogenerated electrons are accumulated on the surface of the PT-Sb<sub>2</sub>S<sub>3</sub> films. Such accumulation might be occurring in defective energy levels or surface defects, which may eventually act as recombination centers.<sup>58,59</sup> As recently reported,<sup>58-60</sup> the surface defects may be assigned to electron/hole trap sites, dangling bond, mismatching lattice, interdiffusion, antisite defects, etc., which are probably located above the valence band of Sb<sub>2</sub>S<sub>3</sub>. The accumulation of the photogenerated electrons may have also taken place in sulfur vacancies of PT-Sb<sub>2</sub>S<sub>3</sub>, which were probably generated during the N<sub>2</sub> plasma treatment. These vacancies might have been formed from the ejection of sulfur atoms that occurs due to the collision of the N<sub>2</sub> plasma species against the surface of the Sb<sub>2</sub>S<sub>3</sub> films. Ejection of atoms (also known as the etching effect) can occur in the event that species from plasma collide against films' surface with high kinetic energy.<sup>61</sup> Formation of sulfur vacancies from plasma treatment has been reported for several sulfide-based compounds.<sup>36,62,63</sup> Based on all of these, the observed reduction of  $\sigma_{\rm acc}$  values for the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films might be due to the extraction of the trapped electrons from the PT-Sb<sub>2</sub>S<sub>3</sub> film surface by the  $MoS_r$  co-catalyst. Extraction of carriers from the semiconductor's surface by a co-catalyst was also observed for hematite films superficially modified with cobalt.<sup>54</sup> Additionally, the observed decrease of  $\sigma_{\rm acc}$  values in the surface implies a smaller probability of the electron-hole recombination process for the  $PT-Sb_2S_3/MoS_x$  films, which

explains their photoelectroactivity enhancement and the  $E_{on}$  shifting toward less negative values (see Figure 6).

Seeking to gain further understanding of the photoelectroresponse enhancement of the  $PT-Sb_2S_3/MoS_x$  system, Mott–Schottky plots were obtained and are shown in Figure 8



**Figure 8.** Mott–Schottky plots for  $PT-Sb_2S_3$  and  $PT-Sb_2S_3/(1 \text{ min})-MoS_x$  films. The electrolyte was an N<sub>2</sub>-saturated solution of 1.0 mol  $L^{-1}$  H<sub>2</sub>SO<sub>4</sub> at pH 0.6.

for the PT-Sb<sub>2</sub>S<sub>3</sub> film before and after superficially modified with MoS<sub>x</sub> photoelectrodeposited for 1 min. Only the 1 min photoelectrodeposition time of MoS<sub>x</sub> was chosen as the other photoelectrodeposition times did not provide significant photoelectroresponse enhancement of the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> system (see Figure 6b). The Mott–Schottky curves in Figure 8 presented a negative slope for both films, meaning that these materials are p-type semiconductors as previously discussed at the beginning of Figure 6a. The Mott–Schottky plots also provided the means to estimate  $E_{\rm fb}$  via eq 4.<sup>64,65</sup>

$$E_{\rm fb} \left( \text{vs Ag/AgCl/Cl}_{(\text{sat. KCl})} \right) \approx -\frac{\text{intercept}}{\text{slope}} - \frac{kT}{e}$$
 (4)

in which k is the Boltzmann constant ( $1.38 \times 10^{-23} \text{ J K}^{-1}$ ), T is the absolute temperature (298.15 K), e is the elementary

charge  $(1.60 \times 10^{-19} \text{ C})$ , and the slope and intercept values were obtained from the linear equations in Figure 8.

Employing the parameters of the linear equation (slope and intercept) from Figure 8 in eq 4, it provided  $E_{\rm fb}$  values of -0.01 and 0.27 V for bare PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> films, respectively. Compared to the bare PT-Sb<sub>2</sub>S<sub>3</sub> film,  $E_{\rm fb}$  shifted 280 mV toward less negative values for the PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> film, which is linked to the co-catalytic behavior of the MoS<sub>x</sub> for the HER as already observed in the linear sweep voltammograms of Figure 6a.

Finally, additional understanding about the photoelectroresponse enhancement for the PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> system was achieved by the EIS analyses, which were obtained under illumination and polarized at -0.2 V (cf. Figure 9a). For the sake of comparison, this experiment was also performed for the bare PT-Sb<sub>2</sub>S<sub>3</sub> film. According to Figure 9a, the complex-plane diagram of both films displayed at least one semicircle, and this might be ascribed to the occurrence of the interfacial charge transfer processes. To fully unravel the underlying photophysical and electrochemical processes, the diagrams in Figure 9a were carefully fitted to an electrical circuit model, which is displayed as an inset in Figure 9a. The employed circuit was composed of a solution resistance  $(R_s)$  connected in series with two RC components  $(R_{ct,sc}/CPE_{sc} \text{ and } R_{ct,d}/CPE_{d})$ ; these components in the Bode diagrams (cf. Figure 9b) are associated with the asymmetrical broad peak for both films. Keeping in mind that the electronic processes in the semiconductor's bulk are usually faster than the charge transfer processes of ion diffusion in solution, the high-frequency domain is assigned to processes occurring in the semiconductor, which is represented by the  $R_{ct,sc}$  and  $CPE_{sc}$ components.<sup>66</sup> The former and latter components are the charge transfer resistance and the capacitance in the space charge of the semiconductor, respectively. The low-frequency domain is designated to the charge transfer event at the semiconductorlelectrolyte interface. This phenomenon is represented by the R<sub>ct,d</sub> and CPE<sub>d</sub> components which corresponded to the charge transfer resistance and the double-layer capacitance at the semiconductorlelectrolyte



Figure 9. (a) Complex-plane impedance diagrams and (b) Bode diagrams at -0.2 V vs Ag/AgCl/Cl<sub>(sat. KCl)</sub><sup>-</sup> and under solar light simulator (AM1.5G and 100 mW cm<sup>-2</sup>) for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> films. The electrolyte was a N<sub>2</sub>-saturated solution of 1.0 mol L<sup>-1</sup> H<sub>2</sub>SO<sub>4</sub> at pH 0.6.

Table 1. Resistance and Capacitance Values of the Electrical Circuit Model Used to Fit the Complex-Plane Impedance Diagrams

sample	$(\Omega \text{ cm}^2)$	$\begin{pmatrix} R_{ m ct,sc} \\ (\Omega \  m cm^2) \end{pmatrix}$	$(\Omega \ \mathrm{cm}^{2})$	$Q_{sc}^{\ a} \left( \Omega^{-1} \ \mathrm{cm}^{-2} \ \mathrm{s}^{\mathrm{lpha f, sc}}  ight)$	$Q_{\mathrm{d}}^{\ a} \; (\Omega^{-1} \; \mathrm{cm}^{-2} \; \mathrm{s}^{\mathrm{af,d}})$	$C_{\rm sc}^{\ b}$ ( $\mu \rm F \ cm^{-2}$ )	$C_{\rm d}^{\ b}$ ( $\mu \rm F \ cm^{-2}$ )
PT-Sb <sub>2</sub> S <sub>3</sub>	6.8	499.1	714.6	$3.75 \times 10^{-4} \ (\alpha_{\rm f,sc} = 0.86)$	$7.87 \times 10^{-5} \ (\alpha_{\rm f,d} = 0.63)$	285.5	14.5
$PT-Sb_2S_3/(1 min)-MoS_x$	7.3	223.5	381.4	$1.55 \times 10^{-5} \ (\alpha_{\rm f,sc} = 0.86)$	$9.46 \times 10^{-5} \ (\alpha_{\rm f,d} = 0.71)$	6.2	24.4

 ${}^{a}Q_{sc}$  and  $Q_{d}$  are the pseudocapacitance in the space charge of semiconductor and the double layer at the semiconductorlelectrolyte interface, respectively, while  $\alpha_{f}$  is their corresponding CPE exponent.  ${}^{b}$ The real capacitance of the space charge ( $C_{sc}$ ) of semiconductor and the real capacitance of the double layer ( $C_{d}$ ) at the semiconductorlelectrolyte interface were calculated from eq 5.

Scheme 2. Schematic Representation of the  $MoS_x$  Co-catalyst Effect on the Photoelectroactivity of PT-Sb<sub>2</sub>S<sub>3</sub> Films for PEC H<sub>2</sub> Generation<sup>*a*</sup>



"The solid and dotted orange lines denote the majority and minority events, respectively. Band diagram not drawn to scale.

interface, respectively.<sup>66</sup> For a better fitting of the data, a constant phase element (CPE), i.e., a non-ideal capacitor, was used. The real values of the capacitance density (*C*) were obtained from the CPE parameter (*Q*), also known as CPE-T, and  $R_{ct}$  as shown in eq 5.<sup>67</sup>

$$C = \frac{(QR_{\rm ct})^{1/\alpha_{\rm f}}}{R_{\rm ct}}$$
(5)

in which *Q* is the pseudocapacitance and  $\alpha_f$  is the CPE exponent, also known as CPE-P, which can take a value between 0 and 1. The CPE behaves like an ideal capacitor for  $\alpha_f$  being equal to 1.

The calculated C values as well as the fitted data of each element in the circuit are summarized in Table 1. The percentage error values from the fitting for each element in the circuit are listed in Table S3.

Given the data in Table 1, there was a 2.2-fold decrease of the  $R_{ct,sc}$  value for the PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> film in comparison with the PT-Sb<sub>2</sub>S<sub>3</sub> film. The decreased  $R_{ct,sc}$  for the superficially modified film stands advantageously as it favors a faster transfer of the  $e_{CB}^-$  across the depletion layer and/or the bulk region of the PT-Sb<sub>2</sub>S<sub>3</sub> film.<sup>68</sup> Compared to the PT-Sb<sub>2</sub>S<sub>3</sub> film, there was also a 1.9-fold decrease of the  $R_{ct,d}$ value for the PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> film. Such a decrease was also attributed to a faster transfer of  $e_{CB}^-$  at the PT-Sb<sub>2</sub>S<sub>3</sub>/ (1 min)-MoS<sub>x</sub>lelectrolyte interface.<sup>68,69</sup> Collating these results with the  $\Delta j_{ph}$  responses in Figure 6, the improved photoresponse for the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films is linked to the reduced values of  $R_{ct,sc}$  and  $R_d$  that facilitates carrier transfer to the electrolyte. Another implication was the minimization of the electron—hole recombination process due to the facilitation of the interfacial carrier transfer as noted from the reduction of  $\sigma_{acc}$  values for the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films in Figure 7b.

Concerning the capacitance density values in Table 1,  $C_{sc}$  substantially decreased 46-fold for the PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> compared to the PT-Sb<sub>2</sub>S<sub>3</sub> film. This decrease of  $C_{sc}$  can be a result of increasing the thickness of the space charge  $(d_{sc})$  layer under depletion conditions, which is defined by eq 6.<sup>70</sup>

$$d_{\rm sc} = \frac{\varepsilon_{\rm r} \varepsilon_0}{C_{\rm sc}} \tag{6}$$

in which  $\varepsilon_r$  is the relative permittivity of Sb<sub>2</sub>S<sub>3</sub> and  $\varepsilon_0$  is the permittivity of vacuum.

Increasing  $d_{sc}$  can lead to an enlargement of the (quasi-)Fermi level gradient in the space charge region and consequently enhancement in carrier separation as well as an increase in the photoelectroactivity as seen in Figure 6. The decrease of  $C_{sc}$  for the PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> film can also

be understood by the reduction of electrons accumulated in surface traps (see the discussion of Figure 7b). Still regarding the capacitance density values in Table 1, one can also note that  $C_d$  slightly increased for PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> in comparison with the bare PT-Sb<sub>2</sub>S<sub>3</sub> film. Bearing in mind that  $C_d$  is proportional to the surface area of the solidlelectrolyte interface,<sup>69</sup> the slight increase of  $C_d$  might be associated with the increase of the surface area of the PT-Sb<sub>2</sub>S<sub>3</sub> film by the presence of the nanoparticles of MoS<sub>x</sub>. This probably increased the surface area of the PT-Sb<sub>2</sub>S<sub>3</sub>/(1 min)-MoS<sub>x</sub> film, which may have also contributed to the enhancement of its photoresponse for the HER.

Building on all of these findings presented herein, we believe that the role of  $MoS_x$  on the photoelectroactivity improvement of the PT-Sb<sub>2</sub>S<sub>3</sub> films is due to the minimization of the superficial electron—hole recombination process by the collection of a photogenerated electron trapped in the surface of the PT-Sb<sub>2</sub>S<sub>3</sub> films. Additionally, the presence of  $MoS_x$ enabled minimization of recombination process and consequently improvement of PEC H<sub>2</sub> generation by reducing resistance as well as an increase of  $d_{sc}$ . The contribution of  $MoS_x$  on the photoelectroactivity enhancement of the PT-Sb<sub>2</sub>S<sub>3</sub> films is summarized in Scheme 2. It is worth clarifying that we have not employed  $E_g$  values and electrochemical data to construct the band diagram in Scheme 2, which only served the purpose of better explaining the improvement of H<sub>2</sub> generation on the Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> system.

# CONCLUSIONS

Herein, we have successfully improved the photoelectroactivity of PT-Sb<sub>2</sub>S<sub>3</sub> films for the HER by depositing the earthabundant  $MoS_x$  co-catalyst onto their surface via photoelectrodeposition. Albeit the photoresponse of  $PT-Sb_2S_3/MoS_x$ films did not significantly vary over the  $MoS_x$  photoelectrodeposition time, the presence of the  $MoS_x$  nanoparticles enabled a 2-fold increase of the cathodic  $\Delta j_{\rm ph}$  response. Based on a thorough analysis of the transient  $\Delta j_{ph}$  responses, the enhanced photoelectroactivity was assigned to a smaller probability of the electron-hole recombination process for the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films, as noted from the substantial reduction of the  $\sigma_{\rm acc}$  values. The reduced occurrence of the recombination process is probably linked to the  $MoS_x$  cocatalyst that may have extracted the photogenerated electrons trapped in the defective energy levels (i.e., recombination centers) of the surface of the PT-Sb<sub>2</sub>S<sub>3</sub> films. The minimization of carriers recombination was also verified from the decrease of the  $R_{ct}$  values by approximately 2-fold for the PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films, as observed from the EIS results. Additionally, the PT- $Sb_2S_3/MoS_x$  featured an increase of  $d_{sc}$  meaning improvement of carrier separation or minimized recombination process due to the enlarged gradient of the (quasi-)Fermi level in the space charge region of the PT-Sb<sub>2</sub>S<sub>3</sub> films. The presence of  $MoS_x$ nanoparticles on the PT-Sb<sub>2</sub>S<sub>3</sub> films also resulted in the shift of  $E_{\rm on}$  toward less negative potential values, which indicated that the combination of  $MoS_x$  with the PT-Sb<sub>2</sub>S<sub>3</sub> films co-catalyzed the light-driven HER. Acting in the same manner as the  $E_{\rm on}$ shifting behavior,  $E_{\rm fb}$  from the Mott–Schottky plots shifted to less negative values for the  $PT-Sb_2S_3/MoS_{xy}$  thus substantiating the role of  $MoS_x$  as a co-catalyst of PT-Sb<sub>2</sub>S<sub>3</sub> films for the HER. In view of these results, our work has achieved superlative performance of the  $PT-Sb_2S_3/MoS_x$  films for PEC H<sub>2</sub> generation. Additionally, we have employed electrodeposition, a low-cost methodology, to obtain the  $PT-Sb_2S_3/$ 

 $MoS_x$  system, which is fully composed of earth-abundant and low-toxicity elements. All of these features make our system, i.e.,  $PT-Sb_2S_3/MoS_x$ , a highly promising candidate for a large-scale application of PEC cells in the near future.

# ASSOCIATED CONTENT

#### **Supporting Information**

The Supporting Information is available free of charge at https://pubs.acs.org/doi/10.1021/acsaem.1c03374.

Cyclic voltammograms for  $MoS_x$  photoelectrodeposition; linear sweep voltammograms in the dark and under illumination for UT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> films; high-resolution XPS spectra for UT-Sb<sub>2</sub>S<sub>3</sub>/MoS<sub>x</sub> film; particle size distribution histograms for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films; EDS spectra and EDS quantification plots for PT-Sb<sub>2</sub>S<sub>3</sub> and PT-Sb<sub>2</sub>S<sub>3</sub>/(1, 10, or 20 min)-MoS<sub>x</sub> films; atomic percentage of Sb and S; binding energy assignment; and percentage error values for each circuit element to fit the complex-plane impedance diagrams (PDF)

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#### **Author Contributions**

M.A.d.A. contributed to the conceptualization, methodology, validation, formal analysis, investigation, data curation, and writing—original draft. M.B.C. involved in the conceptualization, investigation, and writing—review and editing. L.H.M. contributed to resources, writing—review and editing, and supervision.

#### Notes

The authors declare no competing financial interest.

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